

Judul:

ISTFA 2001 proceedings of the 27th International Symposium for Testing and Failure Analysis: 11-15 November 2001, Santa Clara Convention Center, Santa Clara, California

Pengarang/Penulis:

Subjek:

Electronics -- Materials -- Testing -- Handbooks, manuals, etc.; Microelectronics -- Materials -- Testing -- Handbooks, manuals, etc.; Microelectronics -- Materials -- Defects -- Handbooks, manuals, etc.; Electronic apparatus and appliances -- Testing -- Handbooks, manuals, etc.; Semiconductors -- Defects -- Handbooks, manuals, etc.

Nomor Panggil:

e20442603

Penerbitan:

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